

SUBCLASS
CLASSIFICATION

U.S. PATENT APPLICATION

APPLICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT	EXAMINER
09/817270	F	430 250	472.23 296	1755 2881	<i>Johnston</i> <i>Young</i>

APPLICANTS
TITLE

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Exposure pattern data generation apparatus associated with standard cell library and charged beam exposure

PTO-2040
12/99

LABEL AREA

(FACE)